# High resolution X-ray microcalorimeter detectors with multilayer absorbers and multilayer transition-edge sensors

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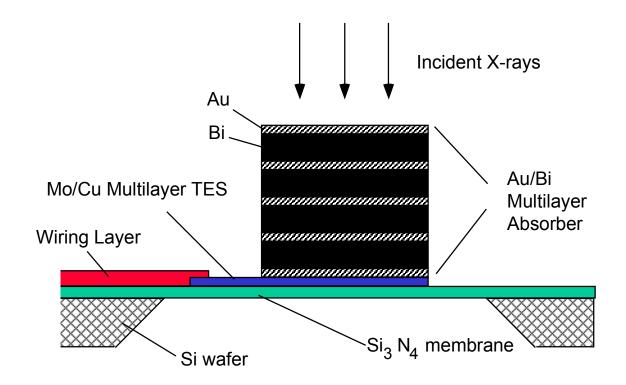
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#### Microcalorimeter Approach



- •Au/Bi multilayers are used to absorb X-rays
- •Mo/Cu multilayer TESs are used to measure the energy of the X-rays



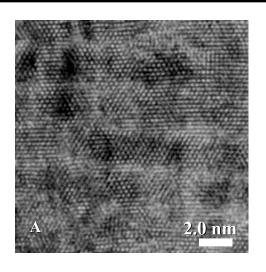
#### Mo/Cu multilayer TES

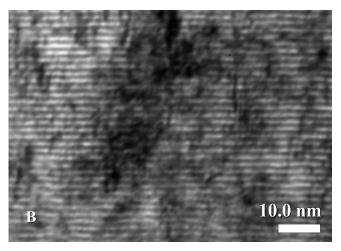


- Mo and Cu are mutually insoluble
  - Mo/Cu can be heated to 400 C to relieve stress
- Superconducting multilayers are very uniform
  - for a sharp transition, the distance between layers should be less than the length scale of the proximity effect
  - bilayers are more limited in the total thickness and resistance
  - thicker films with lower current densities are possible

#### Mo/Cu multilayers







Total thickness = 2500 Å, 115 periods Each period contains:

Mo: 5 monolayers @ 2.224 Å = 11.12 Å Cu: 5 monolayers @ 2.087 Å = 10.43 Å

Thickness accuracy ± 0.2 Å Reproducibility 0.2%

#### Cooper Limit Model



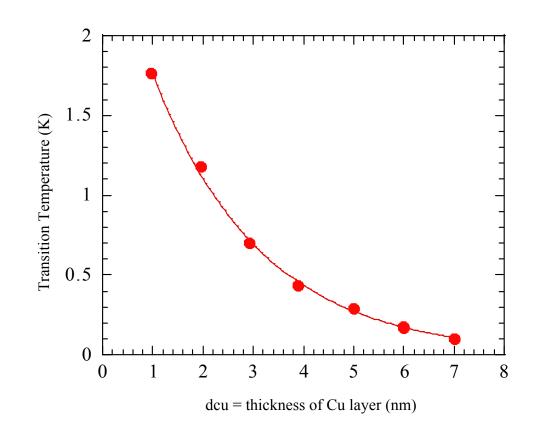
$$Tc = 1.14\theta_D \exp\left(\frac{d \text{ mo} + Bd \text{ cu}}{-d \text{ mo} * \text{N}(0) \text{ V}}\right)$$

Curve fit using two variables:

$$N(0)V = 0.19$$

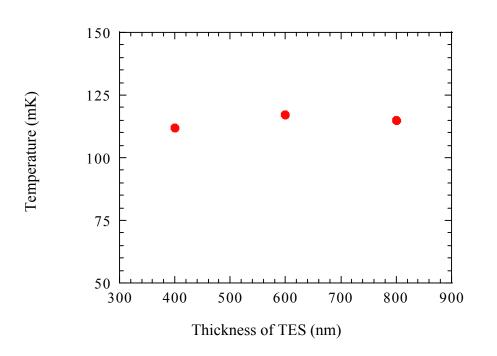
$$B = 0.18$$

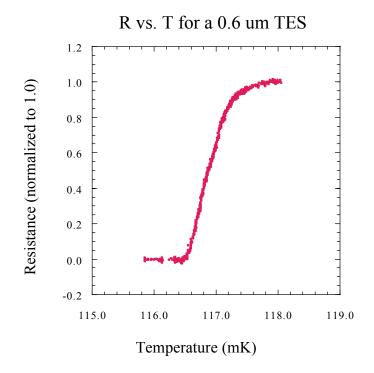
Calculated N(0)V=0.15



#### Te versus Thickness of TES



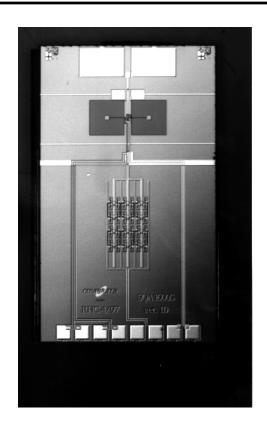


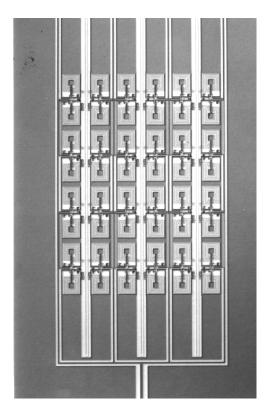


Using multilayers, we can produce smaller pixels without increasing the current density

#### New Commercial SQUID Arrays



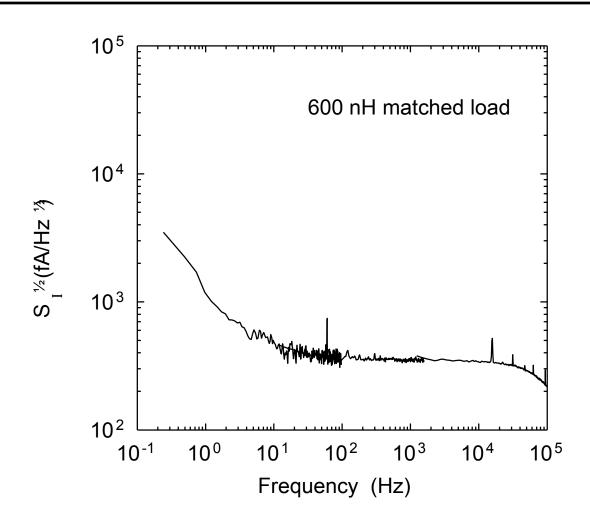




36 Element 2 Stage SQUID developed at Conductus

### Noise Measurement of SQUID Array





#### Testing of SQUID Arrays



- Squid Arrays developed at Conductus
- •No spares of sufficient quality available from the Conductus Run
- •Development continued by Robin Cantor at STAR Cryoelectronics
- •Test new arrays in a few weeks

## Cu/Bi or Au/Bi Multilayer Absorber



•Advantages of Cu/Bi Absorber

Tune Heat Capacity

Maintain Good Thermal Conductivity

- Bi Target Ordered
- •Work have begun work on a sputtering system that will be used for the deposition of Bi

#### Summary



We have measured the properties of Transition Edge Devices

- •Tc is constant with total thickness of the film
- •Tc versus thickness ratio agrees with Cooper Limit Model
- •Transitions widths are typically narrow

We are now investigating

- •Stability of Tc with time and cycling
- •Transition width control with annealing of samples
- •Performance of new commercial SQUID system